

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A Final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

Technical Contact:

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PCN Originator:

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Implementation of change:

Expected 1st Device Shipment Date: 2007/11/19

Earliest Year/Work Week of Changed Product: 47-2007

Change Type Description: Alternate Assembly/Test Location/Qualification

Description of Change (From): FAN5xxxUC WL-CSP products are assembled and tested at the AMKOR facility (A5) in North Carolina, USA

Description of Change (To): FAN5xxxUC WL-CSP products will be assembled at the AMKOR facility (K4) in Korea and tested at the AMKOR facility (T3) in Taiwan.

Reason for Change : Manufacturing activities at the AMKOR facility (A5) in North Carolina will be phased out as this facility will focus on process development.

Qual/REL Plan Numbers : Q20070202

Qualification :

The samples will be front end processed (bumps added) at Amkor's K4 facility (6", Korea) and back end processed (test and singulation) at Amkor's T3 facility (6"/8", Taiwan). One fab lot and three front/back end lots will be used for the tests outlined in the Qualification plan.

Qualification Stress Test and Sample Size Detail

Device #1	FAN5309UCX
Package:	-1
#Leads:	-1

Environment Stress Detail:

	Readpoints	Samples
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Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C	D
ACLV		JESD22-A102	100%RH, 121C	96			77	77	77	77
DOPL		JESD22-A108	125C, 5V	168	500	1000	77	77	77	77
HAST1		JESD22-A110	85%RH, 130C, 5V	96			45	45	45	45
HTSL		JESD22-A103	150C	168	500	1000	77	77	77	77
MOIS			85%RH, 85C	24			100	100	100	100
REFL2			260C	1			100	100	100	100
TMCL2		JESD22-A104	-40C, 125C	500	1000		77	77	77	77

Device #2	TEST
Package:	
#Leads:	

Environment Stress Detail:

				Readpoints			Samples
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A
BTMCL		IPC-9701	-40C, 125C	500	1000	1500	77

Product Id Description : 150 mm WL_CSP products: FAN5350UC

Affected FSIDs :

FAN5350UCX		
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